## **Special Issue**

### Advanced Machine Learning and Scene Understanding in Images and Data

### Message from the Guest Editors

Scene understanding from visual data is a key tool for many applications, including autonomous driving, robotic motion and path planning, industrial automation, and video surveillance. The recent introduction of deep learning techniques has fostered an impressive improvement in performance for approaches dealing with such very challenging tasks. This Special Issue welcomes novel research works presenting effective strategies for scene understanding from both images and 3D data. Possible applications include segmentation, semantic analysis, detection or recognition of objects and people, and many others. Papers focusing on novel segmentation strategies together with machine learning techniques for semantic segmentation and, more generally, scene understanding from visual data are welcome. Covered topics also include techniques exploiting 3D information for the aforementioned applications, both in the form of depth data and of point clouds. Finally, possible submissions also include approaches for solving the critical issue of acquiring training data, including transfer learning, reinforcement learning, domain adaption, and incremental learning strategies for scene understanding.

### **Guest Editors**

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### Deadline for manuscript submissions

closed (20 March 2023)



# Applied Sciences

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## About the Journal

### Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

### Editor-in-Chief

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